# International

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

#### Description

The HEXFET<sup>®</sup> Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

Super-247™

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	105	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	74	A
I <sub>DM</sub>	Pulsed Drain Current ①	390	
$P_D @T_C = 25^{\circ}C$	PowerDissipation	441	W
	Linear Derating Factor	2.9	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 30	V
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>®</sup>	1610	mJ
I <sub>AR</sub>	Avalanche Current <sup>①</sup>	58	A
E <sub>AR</sub>	Repetitive Avalanche Energy <sup>①</sup>	38	mJ
dv/dt	Peak Diode Recovery dv/dt ③	3.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	

#### **Absolute Maximum Ratings**

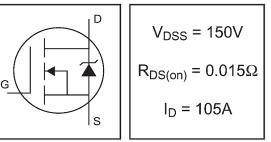
#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
R <sub>0JC</sub>	Junction-to-Case		0.34	
R <sub>0CS</sub>	Case-to-Sink, Flat, Greased Surface	0.24		°C/W
R <sub>0JA</sub>	Junction-to-Ambient		40	

PD - 95896

IRFPS3815PbF

HEXFET<sup>®</sup> Power MOSFET



## IRFPS3815PbF

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### Electrical Characteristics @ $T_J = 25^{\circ}C$ (unless otherwise specified)

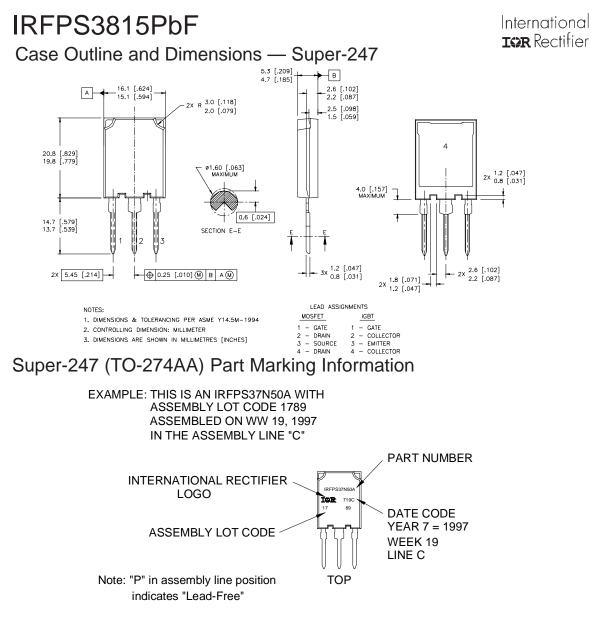
	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	150			V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.18		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	_	—	0.015	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 63A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	3.0		5.0	V	V <sub>DS</sub> = 10V, I <sub>D</sub> = 250µA
9fs	Forward Transconductance	47		—	S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 58A
IDSS	Drain-to-Source Leakage Current			25	μA	V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V
USS	Brain to obtaile Leakage Garrent			250	"~	$V_{DS}$ = 80V, $V_{GS}$ = 0V, $T_{J}$ = 150°C
1	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 30V
IGSS	Gate-to-Source Reverse Leakage			-100		V <sub>GS</sub> = -30V
Qg	Total Gate Charge		260	390		I <sub>D</sub> = 58A
Q <sub>gs</sub>	Gate-to-Source Charge	_	53	80	nC	V <sub>DS</sub> = 120V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge		150	230		V <sub>GS</sub> = 10V⊛
t <sub>d(on)</sub>	Turn-On Delay Time		22			V <sub>DD</sub> = 75V
tr	Rise Time	_	130	—		I <sub>D</sub> = 58A
t <sub>d(off)</sub>	Turn-Off Delay Time		51		ns	R <sub>G</sub> = 1.03Ω
t <sub>f</sub>	Fall Time		60			V <sub>GS</sub> = 10V ④
	Internal Drain Inductance		5.0			Between lead,
L <sub>D</sub>			5.0			6mm (0.25in.)
			10		nH	from package 🔍 🕂
L <sub>S</sub>	Internal Source Inductance		13			and center of die contact
C <sub>iss</sub>	Input Capacitance		6810	—		$V_{GS} = 0V$
Coss	Output Capacitance		1570		pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		480			f = 1.0MHz, See Fig. 5
C <sub>oss</sub>	Output Capacitance		9820		1	$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz$
Coss	Output Capacitance		670		1 1	$V_{GS} = 0V, V_{DS} = 120V, f = 1.0MHz$
Coss eff.	Effective Output Capacitance (5)		1270		1	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 120V$

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current		105		MOSFET symbol	
	(Body Diode)			105	A	showing the
I <sub>SM</sub>	Pulsed Source Current			200		integral reverse 🔍 🛄
	(Body Diode) ①			390		p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage	—		1.3	V	$T_J$ = 25°C, $I_S$ = 58A, $V_{GS}$ = 0V ④
t <sub>rr</sub>	Reverse Recovery Time		270	410	ns	$T_J = 25^{\circ}C, I_F = 58A$
Q <sub>rr</sub>	Reverse RecoveryCharge		2990	4490	nC	di/dt = 100A/µs ⊛
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S+L_D$ )				

Notes:

- Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\textcircled{9} \mbox{ Pulse width } \leq 300 \mu \mbox{s; duty cycle} \leq 2\%.$
- S Coss eff. is a fixed capacitance that gives the same charging time as Coss while VDS is rising from 0 to 80% VDSS
- 3 I\_{SD}  $\leq$  58A, di/dt  $\leq$  450A/µs, V\_{DD}  $\leq$  V\_{(BR)DSS}, T\_J  $\leq$  175°C



Data and specifications subject to change without notice. This product has been designed and qualified for the industrial market. Qualification Standards can be found on IR's Web site.

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